Power MOSFET 30 V, 8 A, N-Channel, SOIC-8

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- SOIC-8 Surface Mount Package Saves Board Space
- This is a Pb-Free Device

Applications

- DC-DC Converters
- Printers

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	6.4	Α
Current R _{θJA} (Note 1)		T _A = 70°C		5.1	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	1.29	W
Continuous Drain		T _A = 25°C	I_{D}	4.9	Α
Current R _{θJA} (Note 2)	Steady	T _A = 70°C		3.9	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	T _A = 25°C	P _D	0.75	W
Continuous Drain		T _A = 25°C	I _D	8.0	Α
Current $R_{\theta JA}$, t < 10 s (Note 1)		T _A = 70°C		6.4	
Power Dissipation R _{0JA} , t < 10 s (Note 1)		T _A = 25°C	P _D	2.0	W
Pulsed Drain Current	sed Drain Current $T_A = 25^{\circ}C$, $t_p = 10 \mu s$			32	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	-55 to +150	°C
Source Current (Body Diode)			I _S	2.0	Α
Single Pulse Drain–to–Source Avalanche Energy ($T_J = 25^{\circ}C$, $V_{DD} = 30$ V, $V_{GS} = 10$ V, $I_L = 11$ A _{pk} , $L = 1.0$ mH, $R_G = 25$ Ω)			E _{AS}	60.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for t = 10 s)			TL	260	°C

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	97	°C/W
Junction-to-Ambient – t < 10 s (Note 1)	$R_{\theta JA}$	62.5	
Junction-to-Foot (Drain)	$R_{\theta JF}$	25	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	167	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surface-mounted on FR4 board using 1 in sq pad, 1 oz Cu
- 2. Surface-mounted on FR4 board using the minimum recommended pad size

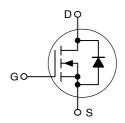


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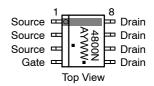
V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	20 mΩ @ 10 V	8 A
30 V	27 mΩ @ 4.5 V	0.4

N-Channel



MARKING DIAGRAM/ PIN ASSIGNMENT





4800N = Device Code A = Assembly Location

Y = Year
WW = Work Week
Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMS4800NR2G	SOIC-8 (Pb-Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			٧
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				26		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	., .,,,	T _J = 25°C			1.0	μΑ
		$V_{GS} = 0 \text{ V}, V_{DS} = 24 \text{ V}$	T _J = 125°C			10	1
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =	±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$	250 μΑ	1.5		3.0	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D =	7.5 A		12.5	20	mΩ
		V _{GS} = 4.5 V, I _D =	6.5 A		20	27	
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D =	7.5 A		21		S
CHARGES, CAPACITANCES AND GA	ATE RESISTAN	ICE	•		*	-	•
Input Capacitance	C _{iss}				940		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = 1.0 MHz,	V _{DS} = 15 V		225		
Reverse Transfer Capacitance	C _{rss}				125		
Total Gate Charge	Q _{G(TOT)}				7.7		nC
Threshold Gate Charge	Q _{G(TH)}	.,			1.1		
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}$	V, I _D = 7.5 A		3.3		
Gate-to-Drain Charge	Q_{GD}				3.2		1
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V, I _D = 7.5 A			15.2		nC
SWITCHING CHARACTERISTICS (No	ote 4)						
Turn-On Delay Time	t _{d(on)}				9.4		ns
Rise Time	t _r	V _{GS} = 10 V, V _{DS} =	= 15 V,		4.0		1
Turn-Off Delay Time	t _{d(off)}	I _D = 1.0 A, R _G =	6.0 Ω		21		1
Fall Time	t _f		•		6.5		1
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V_{SD}		T _J = 25°C		0.75	1.0	V
		$V_{GS} = 0 \text{ V}, I_{S} = 2.0 \text{ A}$	T _J = 125°C		0.59		1
Reverse Recovery Time	t _{RR}		•		17.8		ns
Charge Time	t _a	V_{GS} = 0 V, d_{IS}/d_t = 100 A/ μ s, I_S = 2.0 A			8.3		1
Discharge Time	t _b				9.5		1
Reverse Recovery Charge	Q _{RR}				8.0		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S	T _A = 25°C			0.66		nH
Drain Inductance	L _D				0.20		nH
Gate Inductance	L _G				1.5		nH
Gate Resistance	R_{G}				1.5	3.0	Ω

Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

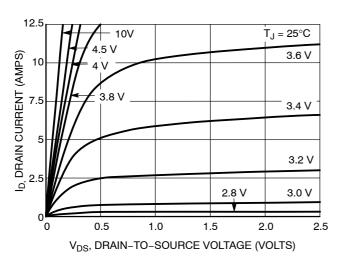
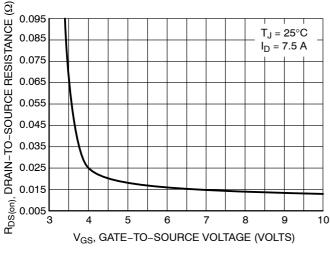


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



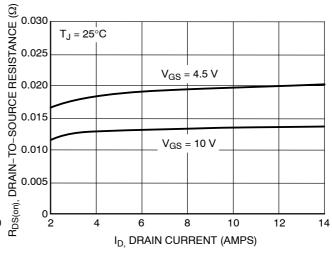
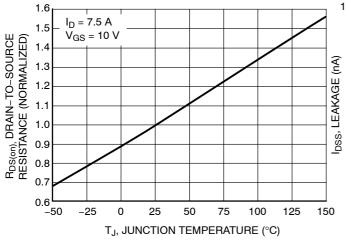


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



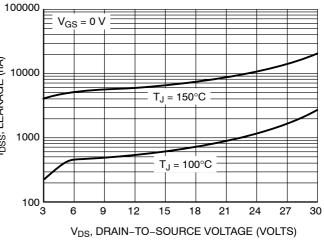


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES

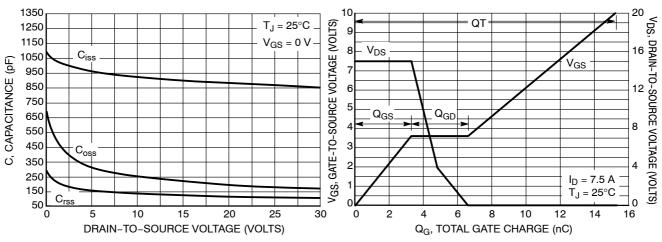


Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

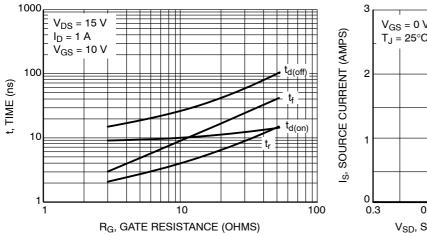


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

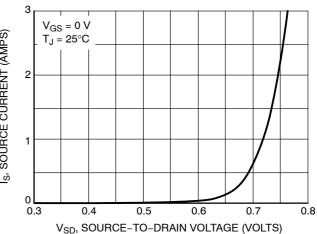


Figure 10. Diode Forward Voltage vs. Current

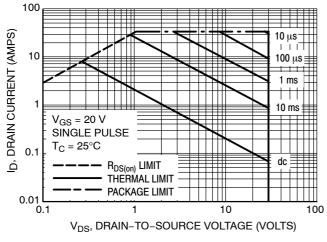


Figure 11. Maximum Rated Forward Biased Safe Operating Area

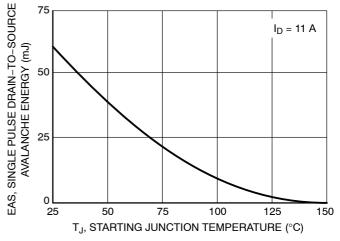
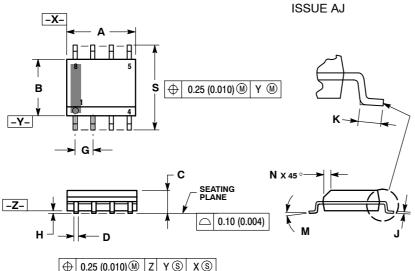


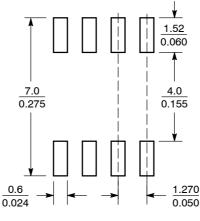
Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

PACKAGE DIMENSIONS

SOIC-8 CASE 751-07



SOLDERING FOOTPRINT*



SCALE 6:1

Mounting Techniques Reference Manual, SOLDERRM/D.

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT
- MAXIMUM MATERIAL CONDITION. 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES			
DIM	MIN	MIN MAX		MAX		
Α	4.80	5.00	0.189	0.197		
В	3.80	4.00	0.150	0.157		
С	1.35	1.75	0.053	0.069		
D	0.33	0.51	0.013	0.020		
G	1.27	1.27 BSC		0 BSC		
Н	0.10	0.25	0.004	0.010		
J	0.19	0.25	0.007	0.010		
K	0.40	1.27	0.016	0.050		
М	0 °	8 °	0 °	8 °		
N	0.25	0.50	0.010	0.020		
s	5.80	6.20	0.228	0.244		

STYLE 12:

- PIN 1. SOURCE
 - 2. SOURCE 3. SOURCE
 - 4. GATE
 - 5 DRAIN
 - DRAIN 6.
 - DRAIN DRAIN

8.

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and

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